IFW

PATENT



Docket No.: 057454-0962

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277

Hideto HIDAKA : Confirmation Number: 4528

Application No.: 10/622,473 : Group Art Unit: 2824

Filed: July 21, 2003 : Examiner: Van Thu T Nguyen

For: THIN FILM MAGNETIC MEMORY DEVICE WITH MEMORY CELLS INCLUDING A

TUNNEL MAGNETIC RESISTIVE ELEMENT

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

·

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

The relevance of Durlam, M. et al., "Nonvolatile RAM based on magnetic tunnel junction elements" and Scheuerlein, R. et al., "A 10ns read and write nonvolatile memory array using a magnetic tunnel junction and FET switch in each cell" is discussed in the

10/622,473

present specification. Each subsequent reference was first cited in an international office action and its relevance discussed therein. A copy of the office action, together with an English language version thereof, is attached for the Examiner's information.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

McDFRMOTT WILL & EMERY LLP

Stephen A. Becker Registration No. 26,527

600 13th Street, N.W. Washington, DC 20005-3096 Phone: 202.756.8000 SAB:sln

Facsimile: 202.756.8087 **Date: July 14, 2005**

Please recognize our Customer No. 20277 as our correspondence address.

SHEET 1 OF 1

INFORMATION DISCLOSURE ATTY, DOCKET NO. SERIAL NO. 057454-0962 10/622,473 "CITATION IN AN **APPLICATION** APPLICANT Hideto HIDAKA (PTO-1449) FILING DATE **GROUP** July 21, 2003 2824 U.S. PATENT DOCUMENTS **EXAMINER'S** CITE Document Number Publication Date Name of Patentee or Pages, Columns, Lines, Where Relevant INITIALS MM-DD-YYYY Applicant of Cited Document Passages or Relevant Figures Appear Number-Kind Code2 (if known) US 6.188.615 B1 02/13/2001 Perner et al. US 6,128,239 10/03/2000 Perner US 6.185.143 02/6/2001 Perner et al. us 5,173,873 12/22/1992 Wu et al. US 2002/0093848 A1 07/18/2002 Thewes et al. Corresponds to DE 199 14 488 C1 US 6,349,054 B1 02/19/2002 Hidaka Corresponds to DE 101 30 829 A1 FOREIGN PATENT DOCUMENTS **EXAMINER'S** Foreign Patent Document Publication Date Name of Patentee or Pages, Columns, Lines Where Translation INITIALS CITE Country Codes-Number 4-Kind Applicant of Cited Document Relevant Figures Appear MM-DD-YYYY Yes No Codes (if known) EP 1 104 092 A2 05/30/2001 **HEWLETT-PACKARD** Х COMPANY, A **DELAWARE** CORPORATION DE 199 14 488 C1 SIEMENS AG 05/31/2000 Corresponds to USP X 2002/0093848 A1 DE 101 30 829 A1 07/18/2002 MITSUBISHI DENKI Corresponds to X 6,349,054 B1 K.K. OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, **EXAMINER'S** INITIALS journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where CITE published. Durlam, M. et al., "Nonvolatile RAM based on magnetic tunnel junction elements" IEEE International Solid-State Circuits Conference, 7 to 9 February 2000, pp. 128-129. Scheuerlein, R. et al., "A 10ns read and write nonvolatile memory array using a magnetic tunnel junction and FET switch in each cell" IEEE International Solid-State Circuits Conference, 7 to 9 February 2000, pp. 128-129. Yamada, K. et al., "A novel sensing scheme for a MRAM with a 5% MR ratio" Symposium on VLSI Circuits, 14 to 16 June 2001, pp. 123-124. Zhang, R. et al., "Windowed MRAM sensing scheme" IEEE International Workshop on Memory and Technology, Design and Testing, 7 to 8 August 2000, pp. 47-55. Kawashima, S. et al.,"A charge-transfer amplifier and an encoded-bus architecture for lowpower SRAM's" IEEE Journal of Solid-State Circuits, Vol. 33, No. 5, May 1998, pp. 793-799. DATE CONSIDERED

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.